

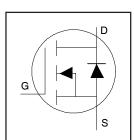


Applications

- Brushed Motor drive applications
- BLDC Motor drive applications
- · Battery powered circuits
- Half-bridge and full-bridge topologies
- Synchronous rectifier applications
- Resonant mode power supplies
- OR-ing and redundant power switches
- DC/DC and AC/DC converters
- DC/AC Inverters

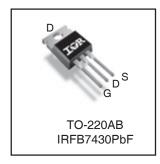
Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free
- RoHS Compliant, Halogen-Free*



HEXFET® Power MOSFET

V _{DSS}	40V
R _{DS(on)} typ.	1.0m Ω
max.	1.3m Ω
I _{D (Silicon Limited)}	409A①
I _{D (Package Limited)}	195A



G	D	S
Gate	Drain	Source

Ordering Information

Base Part Number	Package Type	Standard Pac	Complete Part Number	
		Form Quantity		
IRFB7430PbF	TO-220	Tube	50	IRFB7430PbF

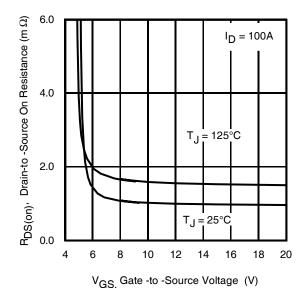


Fig 1. Typical On-Resistance vs. Gate Voltage

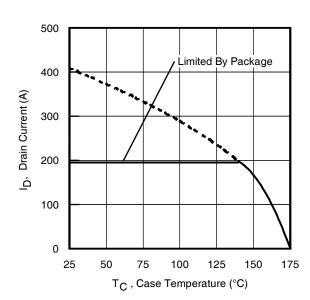


Fig 2. Maximum Drain Current vs. Case Temperature



Absolute Maximum Ratings

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	409①	
$I_D @ T_C = 100^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	289①	
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V (Wire Bond Limited)	195	_ A
I _{DM}	Pulsed Drain Current ②	1524	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	375	W
	Linear Derating Factor	2.5	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
T_J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw	10lbf⋅in (1.1N⋅m)	

Avalanche Characteristics

E _{AS (Thermally limited)}	Single Pulse Avalanche Energy ③	760	mJ
E _{AS (Thermally limited)}	Single Pulse Avalanche Energy ®	1452	
I _{AR}	Avalanche Current ②	See Fig. 14, 15, 22a, 22b	Α
E _{AR}	Repetitive Avalanche Energy ©		mJ

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ®		0.40	
$R_{\theta CS}$	Case-to-Sink, Flat Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

Static @ T_{.I} = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu A$
$_{\Delta}V_{(BR)DSS}/_{\Delta}T_{J}$	Breakdown Voltage Temp. Coefficient		0.014		V/°C	Reference to 25°C, I _D = 1.0mA②
D	Static Drain-to-Source On-Resistance		1.0	1.3	mΩ	V _{GS} = 10V, I _D = 100A ⑤
$R_{DS(on)}$			1.2			$V_{GS} = 6.0V, I_D = 50A$ (§
V _{GS(th)}	Gate Threshold Voltage	2.2		3.9	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
I _{DSS}	Drain-to-Source Leakage Current			1.0	μA	$V_{DS} = 40V$, $V_{GS} = 0V$
				150		$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
	Gate-to-Source Reverse Leakage			-100		V _{GS} = -20V
R _G	Internal Gate Resistance		2.1		Ω	

Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 195A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- ② Repetitive rating; pulse width limited by max. junction temperature.
- $\label{eq:limited_system} \begin{tabular}{ll} \hline \& Limited by T_{Jmax}, starting $T_{J}=25^{\circ}C$, $L=0.15mH$ \\ $R_{G}=50\Omega$, $I_{AS}=100A$, $V_{GS}=10V$. \\ \hline \end{tabular}$
- $\textcircled{4} \quad I_{SD} \leq 100 \text{A}, \ di/dt \leq 990 \text{A}/\mu \text{s}, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ} \text{C}.$

- $^{\circ}$ C_{oss} eff. (TR) is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- $\ \ \,$ C $_{oss}$ eff. (ER) is a fixed capacitance that gives the same energy as C $_{oss}$ while V $_{DS}$ is rising from 0 to 80% V $_{DSS}.$
- $\begin{tabular}{ll} \hline \& & R_{\theta} \mbox{ is measured at T_J approximately 90°C}... \\ \hline \end{tabular}$
- (9) Limited by T_{Jmax} , starting T_J = 25°C, L = 1mH, R_G = 50 Ω , I_{AS} = 54A, V_{GS} =10V.
- * Halogen -Free since April 30, 2014



Dynamic @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	150			S	$V_{DS} = 10V, I_{D} = 100A$
Q_g	Total Gate Charge		300	460	nC	I _D = 100A
Q_{gs}	Gate-to-Source Charge		77			V _{DS} =20V
Q_{gd}	Gate-to-Drain ("Miller") Charge		98			V _{GS} = 10V ⑤
Q _{sync}	Total Gate Charge Sync. (Q _g - Q _{gd})		202			
t _{d(on)}	Turn-On Delay Time		32		ns	V _{DD} = 20V
t _r	Rise Time		105			I _D = 30A
$t_{d(off)}$	Turn-Off Delay Time		160			$R_G = 2.7\Omega$
t _f	Fall Time		100			V _{GS} = 10V ⑤
C _{iss}	Input Capacitance		14240		pF	$V_{GS} = 0V$
C _{oss}	Output Capacitance		2130			V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance		1460			f = 1.0 MHz
C _{oss} eff. (ER)	Effective Output Capacitance (Energy Related) ②		2605			V _{GS} = 0V, V _{DS} = 0V to 32V ⑦
C _{oss} eff. (TR)	Effective Output Capacitance (Time Related)®		2920			V _{GS} = 0V, V _{DS} = 0V to 32V ⑥

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			394①	Α	MOSFET symbol
	(Body Diode)					showing the
I _{SM}	Pulsed Source Current			1576	Α	integral reverse
	(Body Diode) ②					p-n junction diode.
V_{SD}	Diode Forward Voltage		0.86	1.2	V	$T_J = 25$ °C, $I_S = 100$ A, $V_{GS} = 0$ V (S)
dv/dt	Peak Diode Recovery ④		2.7		V/ns	$T_J = 175^{\circ}C$, $I_S = 100A$, $V_{DS} = 40V$
t _{rr}	Reverse Recovery Time		52		ns	$T_J = 25^{\circ}C$ $V_R = 34V$,
			52			$T_J = 125^{\circ}C$ $I_F = 100A$
Q _{rr}	Reverse Recovery Charge		97		nC	$T_J = 25^{\circ}C$ di/dt = 100A/ μ s \odot
			97			T _J = 125°C
I _{RRM}	Reverse Recovery Current		2.3		Α	T _J = 25°C



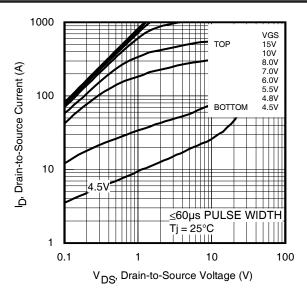


Fig 3. Typical Output Characteristics

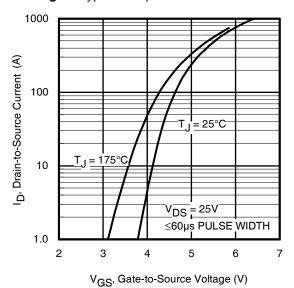


Fig 5. Typical Transfer Characteristics

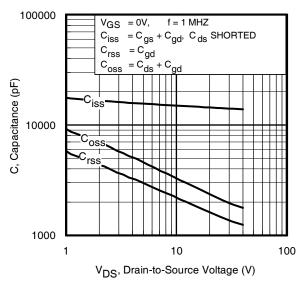


Fig 7. Typical Capacitance vs. Drain-to-Source Voltage

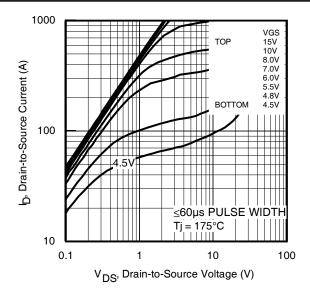


Fig 4. Typical Output Characteristics

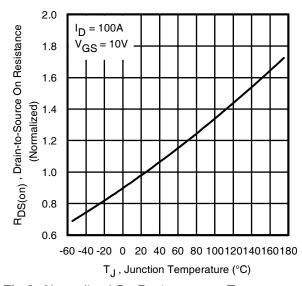


Fig 6. Normalized On-Resistance vs. Temperature

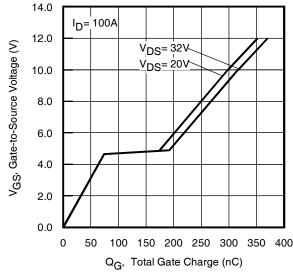


Fig 8. Typical Gate Charge vs. Gate-to-Source Voltage



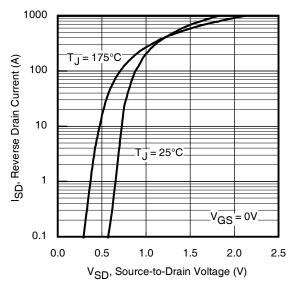


Fig 9. Typical Source-Drain Diode Forward Voltage

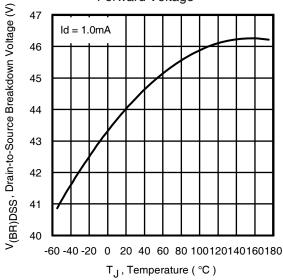


Fig 11. Drain-to-Source Breakdown Voltage

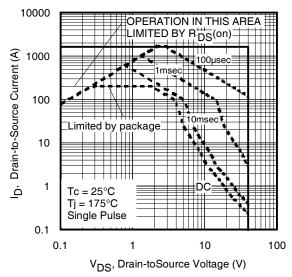


Fig 10. Maximum Safe Operating Area

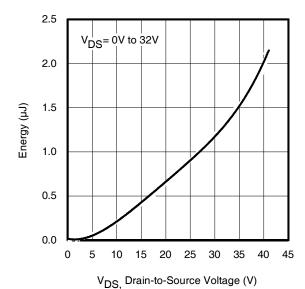


Fig 12. Typical C_{OSS} Stored Energy

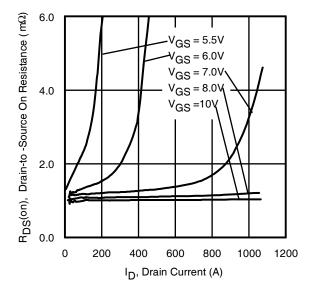


Fig 13. Typical On-Resistance vs. Drain Current



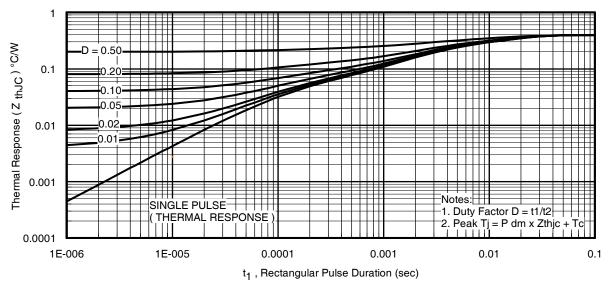


Fig 14. Maximum Effective Transient Thermal Impedance, Junction-to-Case

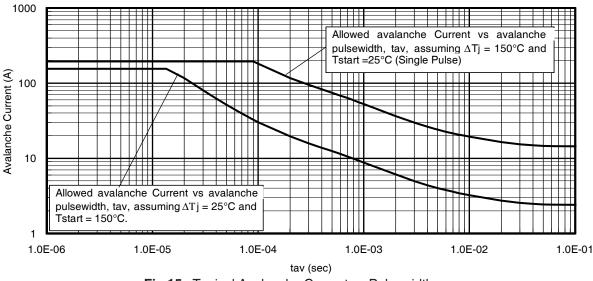


Fig 15. Typical Avalanche Current vs. Pulsewidth

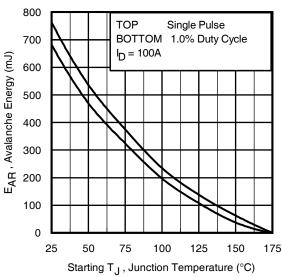


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in
- excess of T_{imax}. This is validated for every part type. 2. Safe operation in Avalanche is allowed as long asT_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.
- 4. P_{D (ave)} = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).

 t_{av} = Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

 $Z_{th,IC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D~(ave)} = 1/2~(~1.3 \cdot BV \cdot I_{aV}) &= \triangle T/~Z_{thJC} \\ I_{av} = 2\triangle T/~[1.3 \cdot BV \cdot Z_{th}] \\ E_{AS~(AR)} &= P_{D~(ave)} \cdot t_{av} \end{split}$$



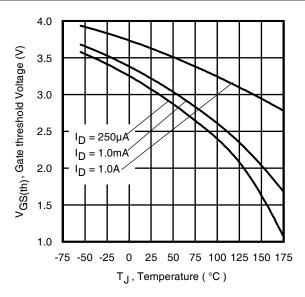


Fig 17. Threshold Voltage vs. Temperature

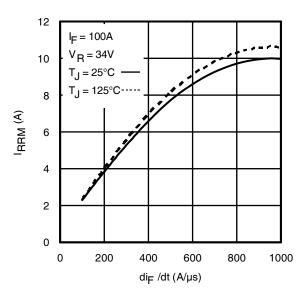


Fig. 19 - Typical Recovery Current vs. dif/dt

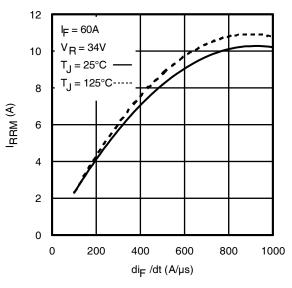


Fig. 18 - Typical Recovery Current vs. di_f/dt

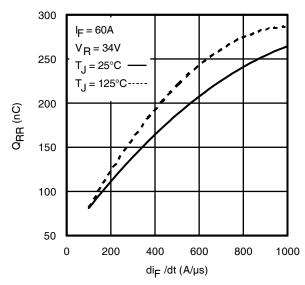


Fig. 20 - Typical Stored Charge vs. dif/dt

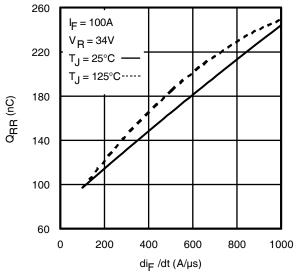


Fig. 21 - Typical Stored Charge vs. dif/dt



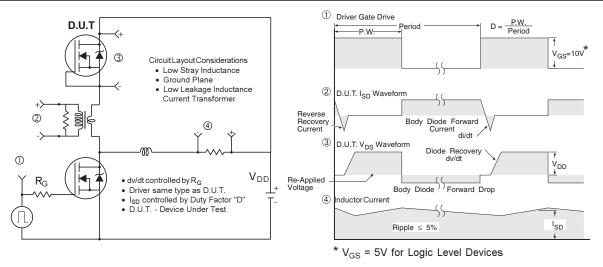


Fig 22. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

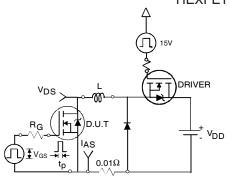


Fig 22a. Unclamped Inductive Test Circuit

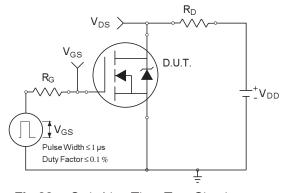


Fig 23a. Switching Time Test Circuit

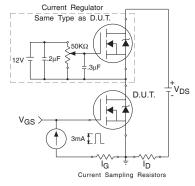


Fig 24a. Gate Charge Test Circuit

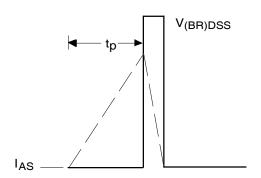


Fig 22b. Unclamped Inductive Waveforms

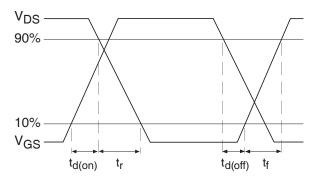


Fig 23b. Switching Time Waveforms

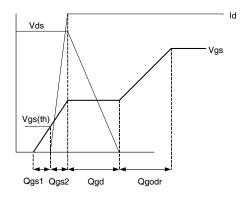
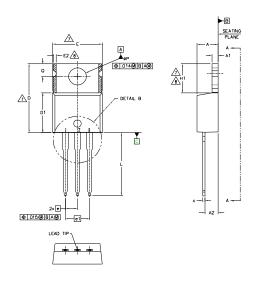


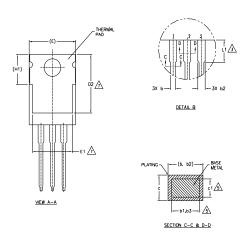
Fig 24b. Gate Charge Waveform



TO-220AB Package Outline

Dimensions are shown in millimeters (inches)





NOTES:

- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.
- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
- LEAD DIMENSION AND FINISH UNCONTROLLED IN L1
- DIMENSION D. D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.

- CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIM	ETERS	INC	HES	
	MIN.	MAX.	MIN.	MAX.	NOTES
Α	3.56	4,83	.140	,190	
A1	1,14	1.40	.045	.055	
A2	2.03	2.92	.080	.115	
b	0.38	1.01	.015	.040	
b1	0.38	0.97	.015	.038	5
b2	1,14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
С	0.36	0.61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	11.68	12.88	.460	.507	7
E	9.65	10.67	.380	.420	4,7
E1	6.86	8.89	.270	.350	7
E2	-	0.76	-	.030	8
e	2.54	BSC	.100	BSC	
e1	5.08	BSC	.200	BSC	
H1	5.84	6.86	.230	.270	7,8
L	12.70	14.73	.500	.580	
L1	3.56	4.06	.140	.160	3
øΡ	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	

LEAD ASSIGNMENTS

<u>HEXFET</u> 1 - GATE

2.- DRAIN 3.- SOURCE

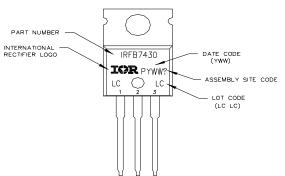
IGBTs, CoPACK

1.- GATE 2.- COLLECTOR 3.- EMITTER

DIODES

1.- ANODE 2.- CATHODE 3.- ANODE

TO-220AB Part Marking Information



MARKING DESCRIPTION PART#: IRFB7430 (P): LEAD FREE RELEASED (Y): LAST DIGIT OF YEAR (WW): WORK WEEK (?): ASSEMBLY SITE CODE (LC LC): LAST 4 DIGITS OF LOT CODE

TO-220AB packages are not recommended for Surface Mount Application.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification information+

Qualification level	Industrial			
	(per JEDEC JESD47F ^{††} guidelines)			
Moisture Sensitivity Level	TO-220 Not applicable			
RoHS compliant	Yes			

[†] Qualification standards can be found at International Rectifier's web site: http://www.irf.com/product-info/reliability/

Revision History

Date	Comment				
	Updated data sheet with new IR corporate template.				
4/22/2014 • Updated package outline and part marking on page 9.					
	Added bullet point in the Benefits "RoHS Compliant, Halogen -Free" on page 1.				
• Updated E _{AS (L=1mH)} = 1452mJ on page 2					
2/19/2015	• Updated note 9 "Limited by T_{Jmax} , starting $T_J = 25$ °C, $L = 1$ mH, $R_G = 50\Omega$, $I_{AS} = 54$ A, $V_{GS} = 10$ V". on page 2				



IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA
To contact International Rectifier, please visit http://www.irf.com/whoto-call/

^{††} Applicable version of JEDEC standard at the time of product release.